

10600148_CLS.txt
Most Frequently Occurring Classifications of Patents Returned
From A Search of 10600148 on September 14, 2004

Original Classifications

11 209/573
7 700/121
4 382/145
4 702/118
2 324/760
2 430/5
2 439/482

Cross-Reference Classifications

14 257/E23.179
13 324/765
11 209/571
9 324/158.1
9 700/116
5 438/14
5 700/224
5 702/187
5 702/82
4 700/226
4 702/117
3 700/108
3 700/109
2 209/583
2 257/E21.525
2 257/E25.013
2 324/704
2 324/754
2 430/22
2 430/311
2 430/394
2 430/396
2 438/17
2 438/691
2 438/692
2 700/117
2 700/215
2 702/118

Combined Classifications

14 257/E23.179
14 324/765
12 209/573
11 209/571
9 324/158.1
9 700/116
8 700/121
6 438/14
6 702/118
5 382/145
5 700/224
5 702/187
5 702/82
4 700/226
4 702/117
3 700/108
3 700/109
2 209/583
2 257/E21.525

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2 257/E25.013
2 324/704
2 324/754
2 324/760
2 430/22
2 430/311
2 430/394
2 430/396
2 430/5
2 438/17
2 438/691
2 438/692
2 439/482
2 700/117
2 700/215

10600148_CLSTITLES.txt
Titles of Most Frequently Occurring Classifications of Patents Returned
From A Search of 10600148 on September 14, 2004

14	257/E23.179	(0 OR, 14 XR)
	Class 257 :	ACTIVE SOLID-STATE DEVICES
	257/E23.176	...For flat cards, e.g., credit cards (EPO)
	257/E23.179	.Marks applied to semiconductor devices or parts, e.g., registration marks, test patterns, alignment structures, wafer maps (EPO)
14	324/765	(1 OR, 13 XR)
	Class 324 :	ELECTRICITY: MEASURING AND TESTING
	324/500	FAULT DETECTING IN ELECTRIC CIRCUITS AND OF ELECTRIC COMPONENTS
	324/537	.Of individual circuit component or element
	324/765	..Test of semiconductor device
12	209/573	(11 OR, 1 XR)
	Class 209 :	CLASSIFYING, SEPARATING, AND ASSORTING SOLIDS
	209/509	SORTING SPECIAL ITEMS, AND CERTAIN METHODS AND APPARATUS (E.G., POCKET TYPE AND LIGHT RESPONSIVE
SORTING,		ETC.) FOR SORTING ANY ITEMS
	209/552	.Condition responsive means controls separating means
	209/571	..Electrical test sensing property of item
	209/573	...Electrical component tested
11	209/571	(0 OR, 11 XR)
	Class 209 :	CLASSIFYING, SEPARATING, AND ASSORTING SOLIDS
	209/509	SORTING SPECIAL ITEMS, AND CERTAIN METHODS AND APPARATUS (E.G., POCKET TYPE AND LIGHT RESPONSIVE
SORTING,		ETC.) FOR SORTING ANY ITEMS
	209/552	.Condition responsive means controls separating means
	209/571	..Electrical test sensing property of item
9	324/158.1	(0 OR, 9 XR)
	Class 324 :	ELECTRICITY: MEASURING AND TESTING
	324/158.1	MISCELLANEOUS
9	700/116	(0 OR, 9 XR)
	Class 700 :	DATA PROCESSING: GENERIC CONTROL SYSTEMS OR SPECIFIC APPLICATIONS
	700/90	SPECIFIC APPLICATION, APPARATUS OR PROCESS
	700/95	.Product assembly or manufacturing
	700/115	..Product tracking (e.g., having product or carrier identification)
	700/116	...Having identification controlled manufacturing operation
8	700/121	(7 OR, 1 XR)
	Class 700 :	DATA PROCESSING: GENERIC CONTROL SYSTEMS OR SPECIFIC APPLICATIONS
	700/90	SPECIFIC APPLICATION, APPARATUS OR PROCESS
	700/95	.Product assembly or manufacturing
	700/117	..Particular manufactured product or operation
	700/121	...Integrated circuit production or

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semiconductor fabrication

- 6 438/14 (1 OR, 5 XR)
Class 438 : SEMICONDUCTOR DEVICE MANUFACTURING: PROCESS
438/14 WITH MEASURING OR TESTING
- 6 702/118 (4 OR, 2 XR)
Class 702 : DATA PROCESSING: MEASURING, CALIBRATING, OR
TESTING
702/108 TESTING SYSTEM
702/117 .Of circuit
702/118 ..Testing multiple circuits
- 5 382/145 (4 OR, 1 XR)
Class 382 : IMAGE ANALYSIS
382/100 APPLICATIONS
382/141 .Manufacturing or product inspection
382/145 ..Inspection of semiconductor device or printed
circuit board
- 5 700/224 (0 OR, 5 XR)
Class 700 : DATA PROCESSING: GENERIC CONTROL SYSTEMS OR
SPECIFIC APPLICATIONS
700/90 SPECIFIC APPLICATION, APPARATUS OR PROCESS
700/213 .Article handling
700/219 ..Associating or disassociating plural articles
700/223 ...Collating or sorting
700/224Having an identification code
- 5 702/187 (0 OR, 5 XR)
Class 702 : DATA PROCESSING: MEASURING, CALIBRATING, OR
TESTING
702/127 MEASUREMENT SYSTEM
702/187 .History logging or time stamping
- 5 702/82 (0 OR, 5 XR)
Class 702 : DATA PROCESSING: MEASURING, CALIBRATING, OR
TESTING
702/1 MEASUREMENT SYSTEM IN A SPECIFIC ENVIRONMENT
702/81 .Quality evaluation
702/82 ..Having judging means (e.g., accept/reject)
- 4 700/226 (0 OR, 4 XR)
Class 700 : DATA PROCESSING: GENERIC CONTROL SYSTEMS OR
SPECIFIC APPLICATIONS
700/90 SPECIFIC APPLICATION, APPARATUS OR PROCESS
700/213 .Article handling
700/225 ..Having an identification code
700/226 ...Identification code determines article
destination
- 4 702/117 (0 OR, 4 XR)
Class 702 : DATA PROCESSING: MEASURING, CALIBRATING, OR
TESTING
702/108 TESTING SYSTEM
702/117 .Of circuit
- 3 700/108 (0 OR, 3 XR)
Class 700 : DATA PROCESSING: GENERIC CONTROL SYSTEMS OR
SPECIFIC APPLICATIONS
700/90 SPECIFIC APPLICATION, APPARATUS OR PROCESS

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700/95 .Product assembly or manufacturing
700/108 ..Performance monitoring

3 700/109 (0 OR, 3 XR)
Class 700 : DATA PROCESSING: GENERIC CONTROL SYSTEMS OR
SPECIFIC APPLICATIONS
700/90 SPECIFIC APPLICATION, APPARATUS OR PROCESS
700/95 .Product assembly or manufacturing
700/108 ..Performance monitoring
700/109 ...Quality control

2 209/583 (0 OR, 2 XR)
Class 209 : CLASSIFYING, SEPARATING, AND ASSORTING SOLIDS
209/509 SORTING SPECIAL ITEMS, AND CERTAIN METHODS AND
APPARATUS (E.G., POCKET TYPE AND LIGHT RESPONSIVE
SORTING,
ETC.) FOR SORTING ANY ITEMS
209/552 .Condition responsive means controls separating
means
209/576 ..Sensing radiant energy reflected, absorbed,
emitted, or obstructed by item or adjunct thereof
209/577 ...Infrared, visible light, or ultraviolet
209/583Reading indicia

2 257/E21.525 (0 OR, 2 XR)
Class 257 : ACTIVE SOLID-STATE DEVICES
257/E21.515Involving use of mechanical auxiliary part
without use of alloying or soldering process, e.g.,
pressure contacts (EPO)
257/E21.521 .Testing or measuring during manufacture or
treatment or reliability measurement, i.e., testing of
parts followed by no processing which modifies parts as
such (EPO)
257/E21.525 ..Procedures, i.e., sequence of activities
consisting of plurality of measurement and correction,
marking or sorting steps (EPO)

2 257/E25.013 (0 OR, 2 XR)
Class 257 : ACTIVE SOLID-STATE DEVICES
257/E25.001 ASSEMBLIES CONSISTING OF PLURALITY OF
INDIVIDUAL SEMICONDUCTOR OR OTHER SOLID-STATE DEVICES
(EPO)
257/E25.002 .All devices being of same type, e.g.,
assemblies of rectifier diodes (EPO)
257/E25.003 ..Devices not having separate containers (EPO)
257/E25.01 ...Device consisting of plurality of
semiconductor or other solid state devices or components
formed in or on common substrate, e.g., integrated
circuit
device (EPO)
257/E25.013Stacked arrangements of devices (EPO)

2 324/704 (0 OR, 2 XR)
Class 324 : ELECTRICITY: MEASURING AND TESTING
324/600 IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES
REPRESENTATIVE OF ELECTRICAL STIMULUS/RESPONSE
RELATIONSHIPS
324/649 .Lumped type parameters
324/691 ..Using resistance or conductance measurement

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324/704 ...With ratio determination

2 324/754 (0 OR, 2 XR)
 Class 324 : ELECTRICITY: MEASURING AND TESTING
 324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
 ELECTRIC COMPONENTS
 324/537 .Of individual circuit component or element
 324/754 ..With probe elements

2 324/760 (2 OR, 0 XR)
 Class 324 : ELECTRICITY: MEASURING AND TESTING
 324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
 ELECTRIC COMPONENTS
 324/537 .Of individual circuit component or element
 324/754 ..With probe elements
 324/760 ...With temperature control

2 430/22 (0 OR, 2 XR)
 Class 430 : RADIATION IMAGERY CHEMISTRY: PROCESS,
 COMPOSITION, OR PRODUCT THEREOF
 430/22 REGISTRATION OR LAYOUT PROCESS OTHER THAN COLOR
 PROOFING

2 430/311 (0 OR, 2 XR)
 Class 430 : RADIATION IMAGERY CHEMISTRY: PROCESS,
 COMPOSITION, OR PRODUCT THEREOF
 430/269 IMAGING AFFECTING PHYSICAL PROPERTY OF
 RADIATION SENSITIVE MATERIAL, OR PRODUCING NONPLANAR OR
 PRINTING SURFACE - PROCESS, COMPOSITION, OR PRODUCT
 430/311 .Making electrical device

2 430/394 (0 OR, 2 XR)
 Class 430 : RADIATION IMAGERY CHEMISTRY: PROCESS,
 COMPOSITION, OR PRODUCT THEREOF
 430/394 PLURAL EXPOSURE STEPS

2 430/396 (0 OR, 2 XR)
 Class 430 : RADIATION IMAGERY CHEMISTRY: PROCESS,
 COMPOSITION, OR PRODUCT THEREOF
 430/396 EFFECTING FRONTAL RADIATION MODIFICATION DURING
 EXPOSURE, E,G., SCREENING, MASKING, STENCILING, ETC.

2 430/5 (2 OR, 0 XR)
 Class 430 : RADIATION IMAGERY CHEMISTRY: PROCESS,
 COMPOSITION, OR PRODUCT THEREOF
 430/4 RADIATION MODIFYING PRODUCT OR PROCESS OF
 MAKING
 430/5 .Radiation mask

2 438/17 (0 OR, 2 XR)
 Class 438 : SEMICONDUCTOR DEVICE MANUFACTURING: PROCESS
 438/14 WITH MEASURING OR TESTING
 438/17 .Electrical characteristic sensed

2 438/691 (0 OR, 2 XR)
 Class 438 : SEMICONDUCTOR DEVICE MANUFACTURING: PROCESS
 438/689 CHEMICAL ETCHING
 438/690 .Combined with the removal of material by
 nonchemical means (e.g., ablating, abrading, etc.)
 438/691 ..Combined mechanical and chemical material
 removal

- 2 438/692 (0 OR, 2 XR)
 Class 438 : SEMICONDUCTOR DEVICE MANUFACTURING: PROCESS
 - 438/689 CHEMICAL ETCHING
 - 438/690 .Combined with the removal of material by
 nonchemical means (e.g., ablating, abrading, etc.)
 - 438/691 ..Combined mechanical and chemical material
 removal
 - 438/692 ...Simultaneous (e.g., chemical-mechanical
 polishing, etc.)

- 2 439/482 (2 OR, 0 XR)
 Class 439 : ELECTRICAL CONNECTORS
 - 439/476.1 INCLUDING HANDLE OR DISTINCT MANIPULATING MEANS
 - 439/481 .Randomly manipulated implement
 - 439/482 ..Test probe

- 2 700/117 (0 OR, 2 XR)
 Class 700 : DATA PROCESSING: GENERIC CONTROL SYSTEMS OR
 SPECIFIC APPLICATIONS
 - 700/90 SPECIFIC APPLICATION, APPARATUS OR PROCESS
 - 700/95 .Product assembly or manufacturing
 - 700/117 ..Particular manufactured product or operation

- 2 700/215 (0 OR, 2 XR)
 Class 700 : DATA PROCESSING: GENERIC CONTROL SYSTEMS OR
 SPECIFIC APPLICATIONS
 - 700/90 SPECIFIC APPLICATION, APPARATUS OR PROCESS
 - 700/213 .Article handling
 - 700/214 ..Article storing, retrieval, or arrangement
 (e.g., warehousing, automated library)
 - 700/215 ...Having an identification code

PLUS Search Results for S/N 10600148, Searched September 14, 2004

The Patent Linguistics Utility System (PLUS) is a USPTO automated search system for U.S. Patents from 1971 to the present. PLUS is a query-by-example search system which produces a list of patents that are most closely related linguistically to the application searched. This search was prepared by the staff of the Scientific and Technical Information Center, SIRA.

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L4	40	2 or 3	US-PGPUB ; USPAT	OR	ON	2004/09/14 08:43
L5	49	("5915231" "6049624" "6067507" "6208947" "6226394" "6226394" "6363329" "6400840" "6588854" "6594611" "5907492" "6363295" "6553276" "5859803" "5426072" "5844803" "5856923" "5927512" "6100486" "6122563" "6147316" "6180527" "6307171" "6350959" "6365860" "6365861" "6373011" "6427092" "6437271" "6504123" "6703573" "4387946" "6344401" "5497381" "6307755" "5532612" "6060895" "5972798" "6608385" "6641430" "6676438" "6750136" "5726920" "4343878" "4442188" "5898186" "5976899" "5994915" "6072574" "6091249").pn.	US-PGPUB ; USPAT	OR	ON	2004/09/14 08:43